RSM120040W

N-Channel SiC Power MOSFET

V_{DS}	=	1200	V
$R_{DS(on)}$	=	40	$m\Omega$
$I_D@25\text{C}$	=	68	A

Features

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitance
- Easy to Parallel and Simple to Drive

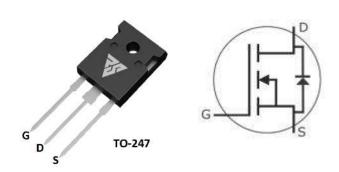
Benefits

- Higher System Efficiency
- Reduced Cooling Requirements
- Increased Power Density
- Increased System Switching Frequency

Applications

- Renewable Energy
- EV Battery Chargers
- High Voltage DC/DC Converters
- Switch Mode Power Supplies

Package



Part Number	Package
RSM120040W	TO-247-3

Maximum Ratings (Tc=250 unless otherwise specified)

Symbol	Parameter	Value	Unit Test Conditions		Note
V _{DSmax}	Drain-Source Voltage	1200	V V _{GS} =0V, I _D =100μA		
V _{GSmax}	Gate-Source Voltage	-8/+22 V A		Absolute maximum values	
V_{GSop}	Gate-Source Voltage	-4/+18	-4/+18 V Recommended operational values		
I _D Continuous Drain Curren	Continuous Drain Current	68		V _{GS} =18V, T _c =25 C	
	Continuous Drain Current	49	Α	V _{GS} =18V, T _c =100 C	
I _{D(pulse)}	Pulsed Drain Current	100	Α	Pulse width t _p limited by T _{Jmax}	
P _D	Power Dissipation	340	W	T _c =25 C , T _J =175 C	
	Operating Junction and Storage	FF 40 147F	5 C		
T _J , T _{STG}	Temperature	-55 to +175			

RSM120040W

Electrical Characteristics (Tc=250 unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	Note
V _{(BR)DSS}	Drain-Source Breakdown Voltage	1200	/	/	V	V _{GS} =0V, I _D =100μA	
	Gate Threshold Voltage	1.9	2.6	4.0	V	V _{DS} =V _{GS} , I _D =9.5mA	
V _{GS(th)}		/	1.8	/		V _{DS} =V _{GS} , I _D =9.5mA, T _J =175 C	
I _{DSS}	Zero Gate Voltage Drain Current	/	1	100	μА	V _{DS} =1200V, V _{GS} =0V	
I _{GSS+}	Gate-Source Leakage Current	1	10	250	nA	V _{DS} = 0 V, V _{GS} = 22 V	
I _{GSS-}	Gate-Source Leakage Current	/	10	250	nA	V _{DS} = 0 V, V _{GS} =-8V	
	Drain-Source On-State Resistance	/	40	53	mΩ	V _{GS} =18V, I _D =33.3A	
R _{DS(on)}	Drain-Source On-State Resistance	/	65	/		V _{GS} =18V, I _D =33.3A, T _J =175 C	
g fs	Transconductance	1	21	/	c	V _{DS} =20V, I _D =33.3A	
Pız	Transconductance	/	17.5	/	S	V _{DS} =20V, I _D =33.3A, T _J =175 C	
C _{iss}	Input Capacitance	/	2070	/		V _{GS} =0V	
Coss	Output Capacitance	1	112	/	рF	V _{DS} =1000V	
C _{rss}	Reverse Transfer Capacitance	1	11	/		f=1MHz	
E _{oss}	C _{oss} Stored Energy	1	66	/	μ	V _{AC} =25mV	
E _{ON}	Turn-On Switching Energy	1	1410	/	μյ	V _{DS} =800V, V _{GS} =-4V/18V	
E _{OFF}	Turn-Off Switching Energy	1	750	/	rj	I _D =33A, R _{G(ext)} =2.5Ω, L=100μH	
t _{d(on)}	Turn-On Delay Time	1	17	/			
t _r	Rise Time	1	58	/	nc	V _{DS} =800V, V _{GS} =-4V/18V, I _D =33A	
t _{d(off)}	Turn-Off Delay Time	/	26	/	ns	$R_{G(ext)}=2.5\Omega$, $R_L=20\Omega$	
t _f	Fall Time	1	15	/			
R _{G(int)}	Internal Gate Resistance	/	4.9	/	Ω	f=1MHz, V _{AC} =25mV	
Q _{GS}	Gate to Source Charge	1	34	/		V _{DS} =800V	
\mathbf{Q}_{GD}	Gate to Drain Charge	1	20	/	nC	V _{GS} =-4V/18V	
$\mathbf{Q}_{\scriptscriptstyle{\mathrm{G}}}$	Total Gate Charge	/	121	/		I _D =33A	

Reverse Diode Characteristics

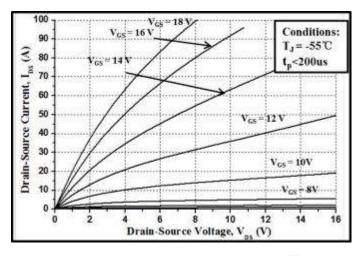
Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
	Diode Forward Voltage	4.5	/	.,	V _{GS} =-4V, I _{SD} =10A	
V_{SD}	Diode Forward Voltage	4.2 / V _{GS} =-4V, I _{SD} =10A, T _J =175 C	V _{GS} =-4V, I _{SD} =10A, T _J =175 C			
Is	Continuous Diode Forward Current	/	51	Α	T _C = 2 5 C	
t _{rr}	Reverse Recover Time	38	/	ns		
Q _{rr}	Reverse Recovery Charge	109	/	nC	V _R =800V, I _{SD} =20A	
I _{rrm}	Peak Reverse Recovery Current	5	/	Α		

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
R _{eJC}	Thermal Resistance from Junction to Case	0.44	/	0/ 1//		
$R_{\theta JA}$	Thermal Resistance from Junction to Ambient	/	40	0 C/ W		

REV: A1 JUL. 2022

Typical Performance



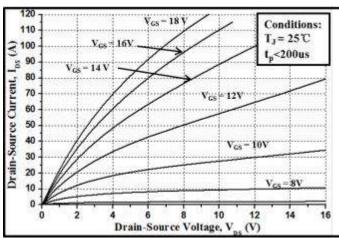
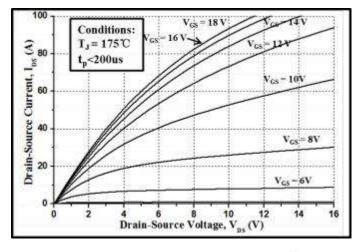


Figure 1. Output Characteristics $T_1 = -55$ C





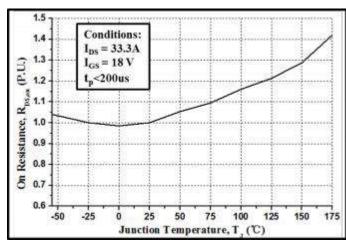
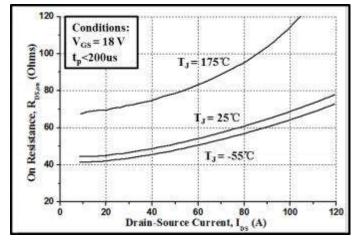


Figure 3. Output Characteristics T_J = 175**C**

Figure 4. Normalized On-Resistance vs. Temperature



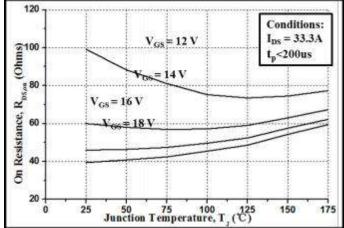


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

Typical Performance

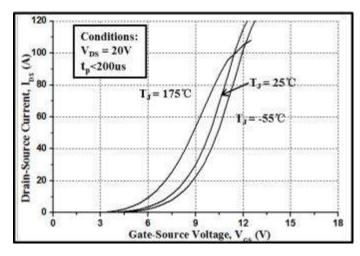


Figure 7. Transfer Characteristic for Various Junction Temperatures

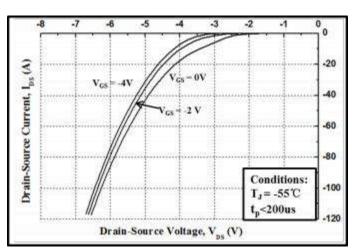
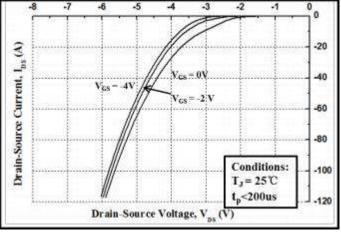


Figure 8. Body Diode Characteristic at -550



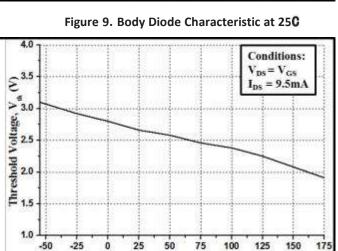


Figure 11. Threshold Voltage vs. Temperature

Junction Temperature, T, (°C)

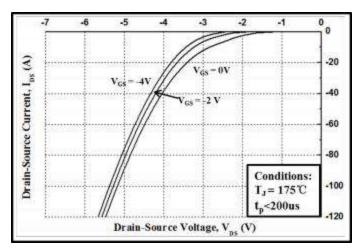


Figure 10. Body Diode Characteristic at 1750

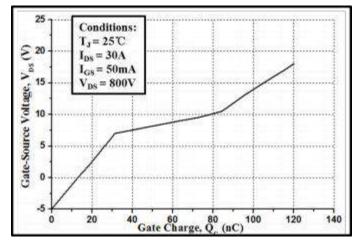


Figure 12. Gate Charge Characteristics

Typical Performance

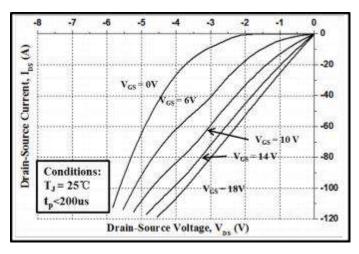


Figure 13. 3rd Quadrant Characteristic at 25C

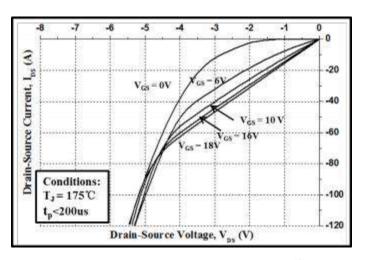


Figure 14. 3rd Quadrant Characteristic at 1750

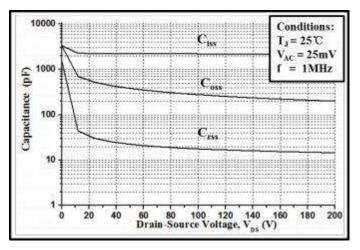


Figure 15. Capacitances vs. Drain-Source Voltage (0 - 200V)

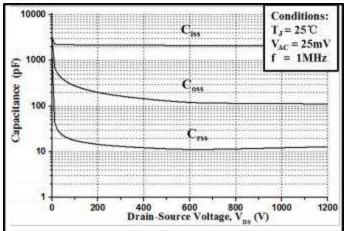
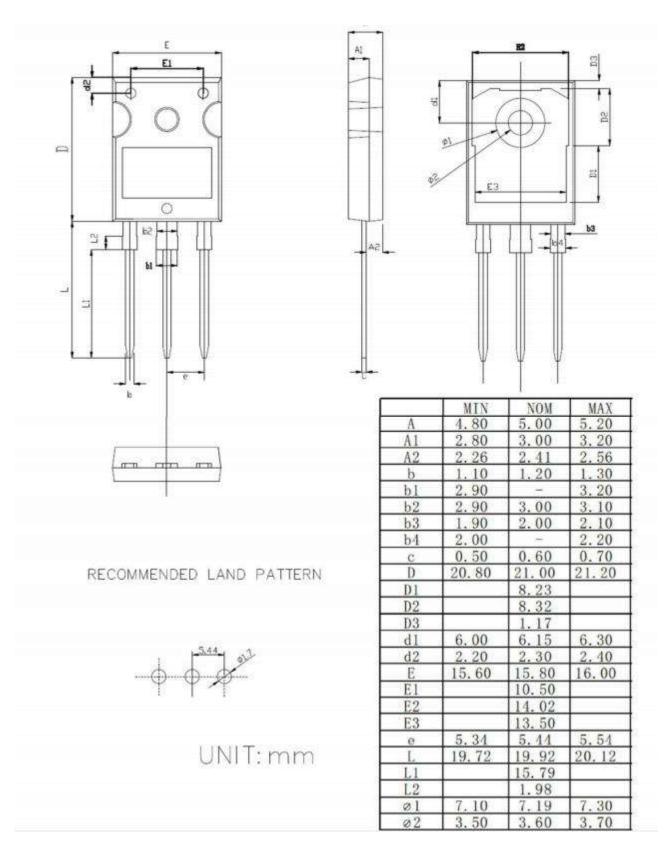


Figure 16. Capacitances vs. Drain-Source Voltage (0 - 1200V)



Package Dimensions



RSM120040W

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REV: A1 JUL. 2022